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\*\* CONTINUING DATA \*\*\*\*\*  
*SAC* *None*

\*\* FOREIGN APPLICATIONS \*\*\*\*\*  
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35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged Examiner's Signature <i>Jonathan R. [Signature]</i> Initials <i>JR</i>				

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TITLE  
 Method of measuring contact resistance of probe and method of testing semiconductor device

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